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Metrology for IoT and Industrial IoT

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Deadline for manuscript submissions:

closed (30 April 2021)

Message from the Guest Editors

This Special Issue is about the reciprocal influence that metrology has on the development of IoT systems and, vice versa, the new opportunities offered by IoT have on the development of new measurement methods and instruments.

The invited contributions are expected to include scientists active in developing instrumentation and measurement methods for IoT and Industrial IoT (including Industry 4.0), new technologies for metrology-assisted production, component measurement, sensors, and associated signal conditioning, and calibration methods for distributed electronic tests.

The session will bring together all the innovative ideas and technologies about measurement challenges in the IoT era, ranging from system architecture, uncertainty analysis, and applications with the aim of increasing the pervasiveness of IoT solutions.













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Message from the Editor-in-Chief

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